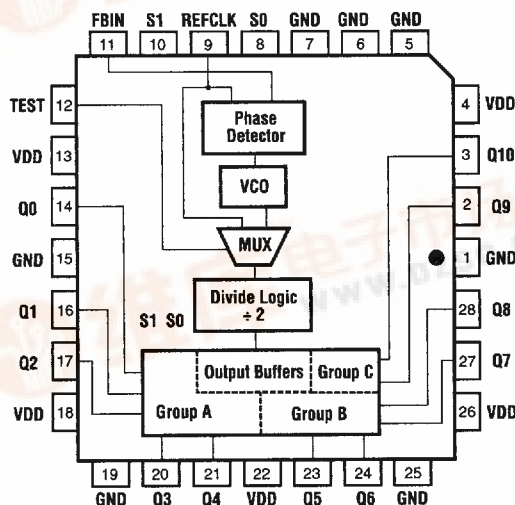


Figure 1. Block Diagram



TriQuint's TQ1090 is a configurable clock buffer which generates 11 outputs, operating over a wide range of frequencies from 33 MHz to 45MHz, 65 MHz to 90 MHz and 130 MHz to 180 MHz. The outputs are available at 1x, 2x and 4x, or at  $\frac{1}{2}x$ ,  $\frac{1}{4}x$  and  $2x$  the reference clock frequency,  $f_{REF}$ . When one of the Group A outputs (Q0–Q4) is used as feedback to the PLL, all Group A outputs will be at  $f_{REF}$ , all Group B outputs (Q5–Q8) will be at  $2x f_{REF}$  and all Group C outputs (Q9, Q10) will be at  $4x f_{REF}$ . When one of the Group B outputs is used as feedback to the PLL, all Group A outputs will be at  $\frac{1}{2}x f_{REF}$ , all Group B outputs will be at  $f_{REF}$  and all Group C outputs will be at  $2x f_{REF}$ . When one of the Group C outputs is used as feedback to the PLL, all Group A outputs will be at  $\frac{1}{4}x f_{REF}$ , all Group B outputs will be at  $\frac{1}{2}x f_{REF}$  and all Group C outputs will be at  $f_{REF}$ .

A very stable internal Phase-Locked Loop (PLL) provides low-jitter operation. This completely self-contained PLL requires no external capacitors or resistors. The PLL's Voltage-Controlled Oscillator (VCO) has a frequency range from 260 MHz to 360 MHz. By feeding back one of the output clocks to FBIN, the PLL continuously maintains frequency and phase synchronization between the reference clock (REFCLK) and each of the outputs.

The phase relationship of the Group A outputs to Group B and C are controlled by the phase select pins S0 and S1. The phase difference can be varied from  $-2t$ ,  $-t$ , 0 or  $+t$ , where  $t = 1/f_{VCO}$ .

TriQuint's patented output buffer design delivers a very low output-to-output skew of 150 ps (max). The TQ1090's symmetrical TTL outputs are capable of sourcing and sinking 30 mA.

## TQ1090

### 11-Output Configurable Clock Buffer

#### Features

- Wide frequency range:  
33 MHz to 45 MHz  
65 MHz to 90 MHz and  
130 MHz to 180 MHz
- Output configurations:  
4 outputs at  $f_{REF}$   
4 outputs at  $2x f_{REF}$   
2 output at  $4x f_{REF}$   
or  
5 outputs at  $\frac{1}{2}x f_{REF}$   
3 outputs at  $f_{REF}$   
2 outputs at  $2x f_{REF}$
- Selectable Phase Shift:  
 $-2t$ ,  $-t$ , 0,  $+t$  ( $t = 1/f_{VCO}$ )
- Low output-to-output skew:  
150 ps (max) within a group
- Near-zero propagation delay  
 $-350 \text{ ps} \pm 500 \text{ ps (max)}$  or  
 $-350 \text{ ps} \pm 1000 \text{ ps (max)}$
- TTL-compatible I/O with 30 mA output drive
- Ideal for Power PC™ designs
- 28-pin J-lead surface-mount package

## TQ1090

### Functional Description

The core of the TQ1090 is a Phase-Locked Loop (PLL) that continuously compares the reference clock (REFCLK) to the feedback clock (FBIN), maintaining a zero frequency difference between the two. Since one of the outputs is always connected to FBIN, the PLL keeps the propagation delay between the outputs and the reference clock within -350 ps  $\pm$  500 ps for the TQ1090-MC500, and within -350 ps  $\pm$  1000 ps for the TQ1090-MC1000.

The internal Voltage-Controlled Oscillator (VCO), has an operating range of 260 MHz to 360 MHz, as shown in Table 1. The combination of the VCO and the Divide Logic enables the TQ1090 to operate between 33 MHz and 45 MHz, 65 MHz and 90 MHz, and from 130 MHz to 180 MHz.

The Shift Select pins, S0 and S1, control the phase shift of the Group A outputs (Q0 - Q4), relative to the other outputs. The user can select from four incremental phase shifts as shown in Table 2 (Phase Selection).

The phase shift increment ( $t$ ) is calculated using the following equation:

$$t = \frac{1}{(f_{REF})(n)}$$

Where  $n$  is the divide mode.

In the test mode, the PLL is bypassed and REFCLK is connected directly to the Divide Logic block via the MUX, as shown in Figure 1. This mode is useful for debug and test purposes. The test mode is outlined in Table 3.

The maximum rise and fall time at the output pins is 1.4 ns. All outputs of the TQ1090 are TTL-compatible with 30 mA symmetric drive and a minimum  $V_{OH}$  of 2.4 V.

### Power Up/Reset Synchronization

After power up or reset, the PLL requires time before it achieves synchronization lock. The maximum time required for synchronization (TSYNC) is 500  $\mu$ s.

**Table 1. Frequency Mode Selection**

Test	Output Feedback	Mode	Reference Clock Frequency Range	Output Frequency Range		
				Group A: Q0 - Q4	Group B: Q5 - Q8	Group C: Q9, Q10
0	Group A	+8	35 MHz - 45 MHz	35 MHz - 45 MHz	65 MHz - 90 MHz	130 MHz - 180 MHz
0	Group B	+4	65 MHz - 90 MHz	35 MHz - 45 MHz	65 MHz - 90 MHz	130 MHz - 180 MHz
0	Group C	+2	130 MHz - 180 MHz	35 MHz - 45 MHz	65 MHz - 90 MHz	130 MHz - 180 MHz

**Table 2. Phase Shift Selection**

S0	S1	Phase Shift (Group A: Q0 - Q4)
0	0	+t
1	0	0
0	1	-t
1	1	-2t

**Table 3. Test Mode Selection**

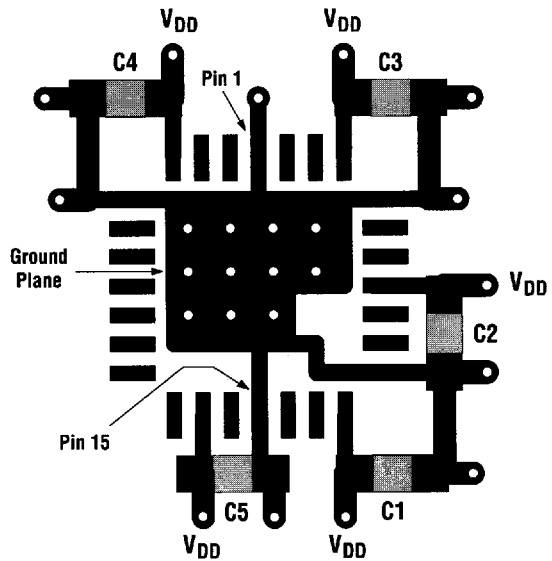
Test	Mode	Ref. Clock	Group A Outputs Q0 - Q4	Group B Outputs Q5 - Q8	Group C Outputs Q9, Q10
1	+2	$f_{REF}$	$f_{REF} \div 8$	$f_{REF} \div 4$	$f_{REF} \div 2$

### Layout Guidelines

Multiple ground and power pins on the TQ1090 reduce ground bounce. Good layout techniques, however, are necessary to guarantee proper operation and to meet the specifications across the full operating range. TriQuint recommends bypassing each of the  $V_{DD}$  supply pins to the nearest ground pin, as close to the chip as possible.

Figure 2 shows the recommended power layout for the TQ1090. The bypass capacitors should be located on the same side of the board as the TQ1090. The  $V_{DD}$  traces connect to an inner-layer  $V_{DD}$  plane. All of the ground pins (GND) are connected to a small ground plane on the surface beneath the chip. Multiple through holes connect this small surface plane to an inner-layer ground plane. The capacitors (C1–C5) are  $0.1\ \mu\text{F}$ . TriQuint's test board uses X7R temperature-stable capacitors in 1206 SMD cases.

Figure 2. Top Layer Layout of Power Pins (Approx. 3.3x)



## TQ1090

### Absolute Maximum Ratings <sup>1</sup>

<b>Storage temperature</b>	-65°C to +150°C
<b>Ambient temperature with power applied <sup>2</sup></b>	-55°C to +100°C
<b>Supply voltage to ground potential</b>	-0.5 V to +7.0 V
<b>DC input voltage</b>	-0.5 V to (V <sub>DD</sub> + 0.5) V
<b>DC input current</b>	-30 mA to +5 mA
<b>Package thermal resistance (MQuad)</b>	$\theta_{JA} = 45^{\circ}\text{C/W}$
<b>Die junction temperature</b>	T <sub>J</sub> = 150°C

### DC Characteristics (V<sub>DD</sub> = +5 V ± 5%, T<sub>A</sub> = 0°C to +70°C) <sup>3</sup>

Symbol	Description	Test Conditions	Limits <sup>4</sup>			
			Min	Typ	Max	Unit
V <sub>OHT</sub>	Output HIGH voltage	V <sub>DD</sub> = Min I <sub>OH</sub> = -30 mA V <sub>IN</sub> = V <sub>IH</sub> or V <sub>IL</sub>	2.4	3.4		V
V <sub>OHC</sub>	Output HIGH voltage	V <sub>DD</sub> = Min I <sub>OH</sub> = -1 mA V <sub>IN</sub> = V <sub>IH</sub> or V <sub>IL</sub>	3.2	4.1		V
V <sub>OL</sub>	Output LOW voltage	V <sub>DD</sub> = Min I <sub>OL</sub> = 30 mA V <sub>IN</sub> = V <sub>IH</sub> or V <sub>IL</sub>		0.27	0.5	V
V <sub>IH</sub> <sup>5</sup>	Input HIGH level	Guaranteed input logical HIGH Voltage for all Inputs	2.0			V
V <sub>IL</sub> <sup>5</sup>	Input LOW level	Guaranteed input logical LOW Voltage for all inputs			0.8	V
I <sub>IL</sub>	Input LOW current	V <sub>DD</sub> = Max V <sub>IN</sub> = 0.40 V		-156	-400	μA
I <sub>IH</sub>	Input HIGH current	V <sub>DD</sub> = Max V <sub>IN</sub> = 2.7 V		0	25	μA
I <sub>I</sub>	Input HIGH current	V <sub>DD</sub> = Max V <sub>IN</sub> = 5.5 V		2	1000	μA
I <sub>DDS</sub> <sup>6</sup>	Power supply current	V <sub>DD</sub> = Max		119	170	mA
V <sub>I</sub>	Input clamp voltage	V <sub>DD</sub> = Min I <sub>IN</sub> = -18 mA		-0.70	-1.2	V

### Capacitance

Symbol	Description	Test Conditions	Min	Typ	Max	Unit
C <sub>IN</sub> <sup>3</sup>	Input capacitance	V <sub>IN</sub> = 2.0 V at f = 1 MHz		6		pF

Notes: 1. Exceeding these parameters may damage the device.

2. Maximum ambient temperature with device not switching and unloaded.

3. These values apply to both TQ1090-MC500 and TQ1090-MC1000.

4. Typical limits are at V<sub>DD</sub> = 5.0 V and T<sub>A</sub> = 25°C.

5. These are absolute values with respect to device ground and all overshoots due to system or tester noise are included.

6. This parameter is measured with device not switching and unloaded.

## AC Characteristics

 $(V_{DD} = +5\text{ V} \pm 5\%, T_A = 0^\circ\text{C to } +70^\circ\text{C})$ 

Symbol	Input Clock (REFCLK)	Test Conditions (Figure 3) <sup>1</sup>	Min	Typ	Max	Unit
$t_{CPWH}$	CLK pulse width LOW	Figure 4	2	—	—	ns
$t_{CPWL}$	CLK pulse width LOW	Figure 4	2	—	—	ns
$t_{IR}$	Input rise time (0.8 V - 2.0V)		—	—	2.0	ns

Symbol	Output Clocks (Q0 - Q10)	Test Conditions (Figure 3) <sup>1</sup>	Min	Typ	Max	Unit
$t_{OR}, t_{OF}$	Rise/fall time (0.8 V - 2.0V)	Figure 4	350	—	1400	ps
$t_{PD1}^2$	CLK $\uparrow$ to FBIN $\uparrow$ (TQ1090-MC500)	Figure 4	-850	-350	+150	ps
$t_{PD2}^2$	CLK $\uparrow$ to FBIN $\uparrow$ (TQ1090-MC1000)	Figure 4	-1350	-350	+650	ps
$t_{SKEW1}^3$	Rise-rise, fall-fall (within group)	Figure 5	—	60	150	ps
$t_{SKEW2}^3$	Rise-rise, fall-fall (group-to-group, aligned)	Figure 6 (skew2 takes into account skew1)	—	75	350	ps
$t_{SKEW3}^3$	Rise-rise, fall-fall (group-to-group, non-aligned)	(skew3 takes into account skew1, 2)	—	—	650	ps
$t_{SKEW4}^3$	Rise-fall, fall-rise	(skew4 takes into account skew3)	—	—	1200	ps
$t_{CYC}^4$	Duty-cycle Variation	Figure 4	-1000	0	+1000	ps
$t_{JP}^5$	Period-to-Period Jitter	Figure 4	—	80	200	ps
$t_{JR}^5$	Random Jitter	Figure 4	—	190	400	ps
$t_{SYNC}^6$	Synchronization Time		—	10	500	$\mu$ s

Notes: 1. All measurements are tested with a REFCLK having a rise time of 0.5 ns (0.8 V to 2.0 V).

2. The PLL maintains alignment of CLK and FBIN at all times. This specification applies to the rising edge only because the input duty cycle can vary while the output duty cycle is typically 50/50. The delay  $t_{PD}$  is measured at the 1.5 V level between CLK and FBIN.

3. Skew specifies the width of the window in which outputs switch, and is measured at 1.5 V. Skew 1 is a subset of skew 2. Skew 2 is a subset of skew 3. Skew 3 is a subset of skew 4. Definition of skew terms is as shown below:

Rise-rise: Skew between rising edges (low to high transitions).

Fall-fall: Skew between falling edges (high to low transitions).

Rise-fall, fall-rise: Skew between rising to falling and falling to rising edges.

Within a group: Skew between outputs of the same group. (e.g. Skew among Group A outputs)

Group-to-group: Skew between outputs of any group. (e.g. Skew between Group A to Group B outputs)

Aligned: Skew between outputs that are in phase.

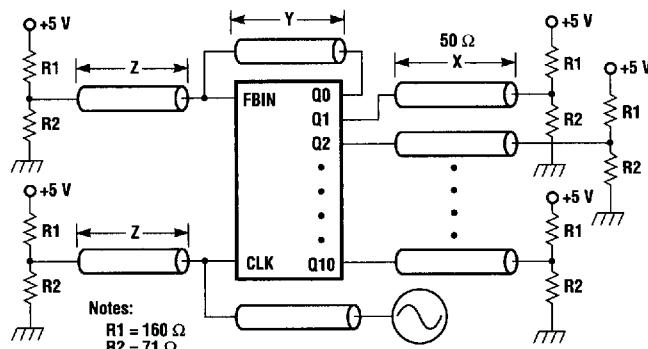
Non-aligned: Skew between outputs that are not in phase.

4. This specification represents the deviation from 50/50 on the outputs.

5. Jitter specifications refer to peak-to-peak value.  $t_{JR}$  is the jitter on the output with respect to the reference clock.  $t_{JP}$  is the jitter on the output with respect to the same output's previous rising edge.

6.  $t_{SYNC}$  is the time required for the PLL to synchronize; this assumes the presence of a CLK signal and a connection from one of the outputs to FBIN.

Figure 3. AC Test Circuit



## Switching Waveforms

Figure 4. General Timing

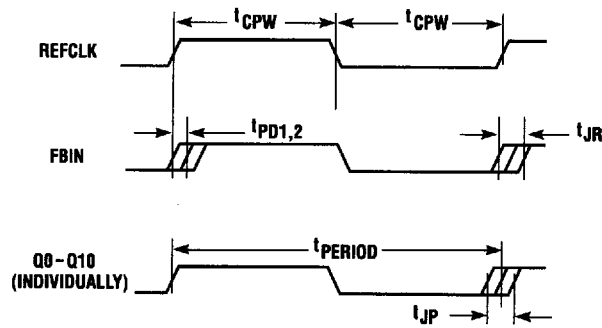


Figure 5.  $t_{SKEW1}$

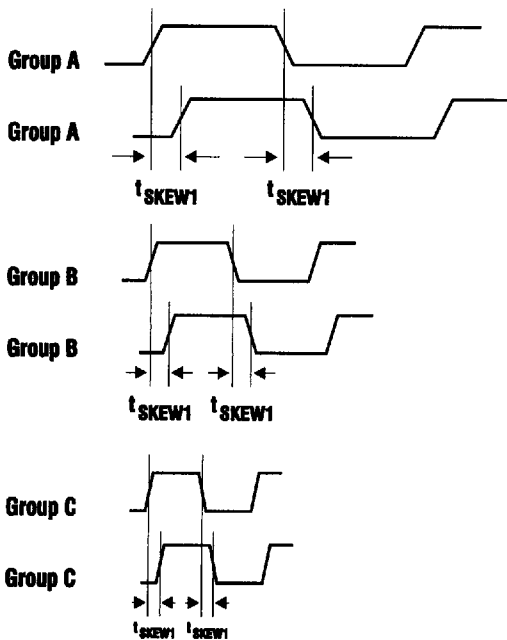
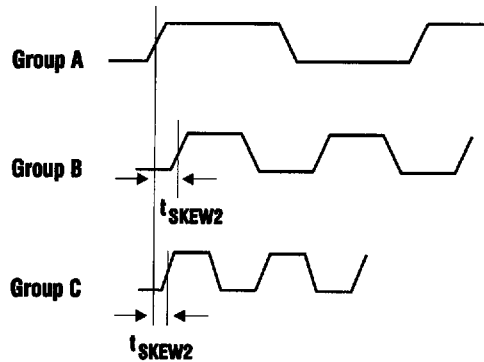
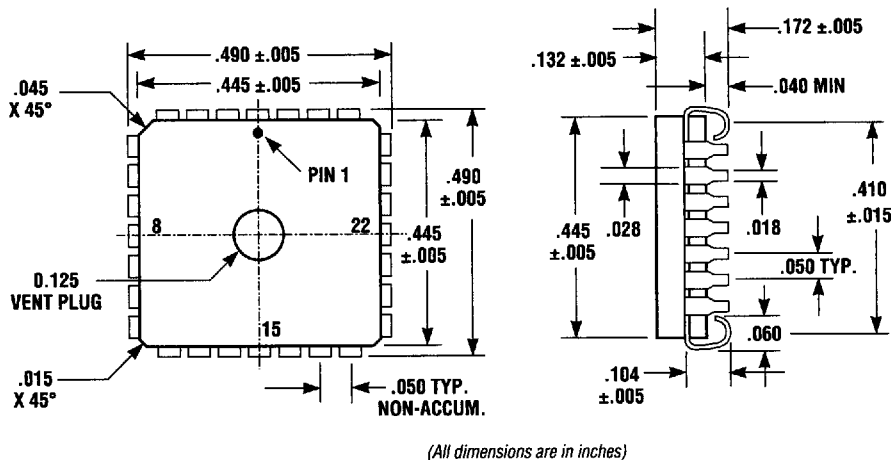


Figure 6.  $t_{SKEW2}$



### 28-Pin MQuad J-Leaded Package Mechanical Specification



### 28-Pin MQuad Pin Description

Pin #	Pin Name	Description	I/O
1	GND	Ground	—
2	Q9	Output Clock 9 (C1)	0
3	Q10	Output Clock 10 (C2)	0
4	VDD	+5 V	—
5	GND	Ground	—
6	GND	Ground	—
7	GND	Ground	—
8	GND	Ground	—
9	REFCLK	Reference Clock	I
10	GND	Ground	—
11	FBIN	Feedback In	I
12	TEST	Test	I
13	VDD	+5 V	—
14	Q0	Output Clock 0 (A1)	0

Pin #	Pin Name	Description	I/O
15	GND	Ground	—
16	Q1	Output Clock 1 (A2)	0
17	Q2	Output Clock 2 (A3)	0
18	VDD	+5 V	—
19	GND	Ground	—
20	Q3	Output Clock 3 (A4)	0
21	Q4	Output Clock 4 (A5)	0
22	VDD	+5 V	—
23	Q5	Output Clock 5 (B1)	0
24	Q6	Output Clock 6 (B2)	0
25	GND	Ground	—
26	VDD	+5 V	—
27	Q7	Output Clock 7 (B3)	0
28	Q8	Output Clock 8 (B4)	0

## TQ1090

### Output Characteristics

The IV characteristics, transition times, package characteristics, device and bond wire characteristics for the TQ1090 are described in Tables 4 through 9 and Figures 9 through 11.

These output characteristics are provided for modelling purposes only. TriQuint does not guarantee the information in these tables and figures.

Figure 9.  $I_{OH}$  vs.  $V_{OH}$

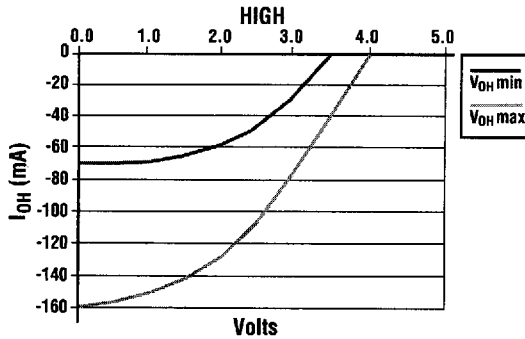


Figure 10.  $I_{OL}$  vs.  $V_{OL}$

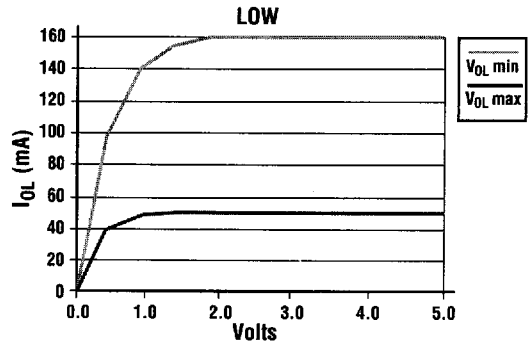


Table 4.  $I_{OH}$  vs.  $V_{OH}$

$V_{OH}$	$I_{OH} \text{ min (mA)}$	$I_{OH} \text{ max (mA)}$
0.0	-70	-160
0.5	-70	-157
1.0	-68	-152
1.5	-65	-142
2.0	-59	-130
2.5	-48	-106
3.0	-29	-79
3.5	0	-42
4.0	0	0
4.5	0	0
5.0	0	0
5.5	40	120
6.0	90	265
6.5	115	350
7.0	135	410
7.5	145	435

Table 5.  $I_{OL}$  vs.  $V_{OL}$

$V_{OL}$	$I_{OL} \text{ min (mA)}$	$I_{OL} \text{ max (mA)}$
-2.5	-145	-435
-2.0	-135	-410
-1.5	-115	-350
-1.0	-90	-265
-0.5	-40	-120
0.0	0	0
0.5	37	97
1.0	49	140
1.5	53	155
2.0	54	157
2.5	54	159
3.0	54	160
3.5	54	160
4.0	54	160
4.5	54	160
5.0	54	160
10.0	54	160

Notes: 1. These are worst-case corners for process, voltage, and temperature.

2. Includes diode to ground current.

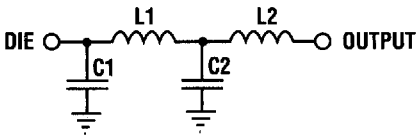


**Table 6. Above  $V_{DD}$  and Below Ground Characteristics**

Diode to GND		Diode to VDD	
V	I (mA)	V	I (mA)
0.0	0	5.0	0
-0.4	0	5.4	0
-0.5	0	5.5	0
-0.6	-5	5.6	5
-0.7	-15	5.7	15
-0.8	-35	5.8	35
-0.9	-55	5.9	55
-1.0	-75	6.0	75
-2.0	-300	7.0	300
-2.5	-350	7.5	350
-3.0	-360	8.0	360

Note: TriQuint does not guarantee diode operation for purposes other than ESD protection.

**Figure 11. Output Model**



**Table 7. Device and Bond Wire Characteristics (Estimated)**

L1	C1
2 nH	10 pF

**Table 8. 28-Pin MQuad Package Characteristics**

L2	C2
1.85 nH	0.40 pF

**Table 9. Rise and Fall Times (Into 0 pF, 50 Ohms to 1.5 V)**

Time (ns)	$T_R$ min (V)	$T_R$ max (V)	$T_F$ min (V)	$T_F$ max (V)
0.0	0.15	0.32	3.20	3.04
0.1	0.15	0.32	3.20	3.04
0.2	0.16	0.32	3.06	2.95
0.3	0.18	0.32	2.86	2.90
0.4	0.23	0.32	2.62	2.68
0.5	0.26	0.32	2.38	2.50
0.6	0.34	0.32	2.17	2.36
0.7	0.46	0.34	2.00	2.22
0.8	0.67	0.39	1.85	2.09
0.9	0.89	0.49	1.69	1.95
1.0	1.12	0.63	1.52	1.86
1.1	1.32	0.86	1.38	1.68
1.2	1.50	1.09	1.26	1.59
1.3	1.73	1.27	1.12	1.49
1.4	1.93	1.45	0.96	1.36
1.5	2.15	1.64	0.83	1.23
1.6	2.75	2.23	0.52	0.95
1.7	2.58	2.00	0.61	1.00
1.8	2.75	2.23	0.52	0.95
1.9	2.90	2.41	0.45	0.91
2.0	3.02	2.50	0.39	0.86
2.1	3.12	2.64	0.33	0.77
2.2	3.17	2.77	0.29	0.73
2.3	3.19	2.86	0.24	0.68
2.4	3.20	2.95	0.21	0.64
2.5	3.20	2.99	0.19	0.59
2.6	3.20	3.02	0.17	0.55
2.7	3.20	3.02	0.16	0.53
2.8	3.20	3.04	0.16	0.50
2.9	3.20	3.04	0.15	0.45
3.0	3.20	3.04	0.15	0.41
3.1	3.20	3.04	0.15	0.40
3.2	3.20	3.04	0.15	0.37
3.3	3.20	3.04	0.15	0.36
3.4	3.20	3.04	0.15	0.32
3.5	3.20	3.04	0.15	0.32

## **TQ1090**

### **Ordering Information**

To order, please specify as shown below:

### **TQ1090-MC**

Propagation delay:

500: -350 ps  $\pm$  500 ps

1000: -350 ps  $\pm$  1000 ps

Temperature range: 0°C to 70°C (Commercial)

Package: 28-lead MQuad

**For more information about the TQ1090 or TriQuint's other System Timing Products, please contact the nearest Sales Office or TriQuint's Customer Service Department:**

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